

## JPFULL (Japan (JP) Patents Full-text)

|                          |  |  |             |                                     |
|--------------------------|--|--|-------------|-------------------------------------|
| <b>Subject Coverage</b>  | All patent-relevant areas of science and technology, i.e., all classes of the International Patent Classification  |  |             |                                     |
| <b>File Type</b>         | Full-text  |  |             |                                     |
| <b>Features</b>          | Thesauri   | International Patent Classification (/IPC), Cooperative Patent Classification (/CPC), European Patent Classification (/EPC and /ICO) |             |                                     |
|                          | <a href="#">Alerts (SDIs)</a>  | Weekly or monthly (weekly is the default)  |             |                                     |
|                          | CAS Registry Number® Identifiers   | <input type="checkbox"/>   | Page Images | <input type="checkbox"/>            |
|                          | <a href="#">Keep &amp; Share</a>   | <input checked="" type="checkbox"/>  | SLART       | <input checked="" type="checkbox"/> |
|                          | Learning Database  | <input type="checkbox"/>   | Structures  | <input type="checkbox"/>            |
| <b>Record Content</b>    | <ul style="list-style-type: none"> <li>• Full-text of patent applications, granted patents, and utilities models published in Japan.</li> <li>• Records are available about ten days after publication date with the complete content</li> <li>• Records contain bibliographic data including patent applicant and inventor, patent, application, priority, and related application data, IPC, CPC, EPC, and ICO classification codes, abstract, and full-text of description and claims.</li> <li>• Abstracts are either machine translated or taken from equivalent documents if available. Machine translated abstracts of documents with kind code A are replaced by human translated text about three months later. Titles are machine translated, which are in case of kind code A documents replaced by human translations about three month later as well. Descriptions and claims are always machine translated.</li> <li>• Title, patent assignee, and inventor are additionally displayable in Japanese characters.</li> <li>• Numeric values of 55 physical and chemical properties are searchable in about 1800 unit variants in all full-text fields.</li> <li>• Database records comprise all documents published for one application.</li> <li>• Legal status data, patent and non-patent citations, and family display formats from the INPADOCDB database are available.</li> <li>• Some of the full-text has been created by Optical Character Recognition (OCR) software. Therefore, characters may be misinterpreted, or portions of the text may be incomplete.</li> </ul> |  |             |                                     |
| <b>File Size</b>         | <ul style="list-style-type: none"> <li>• More than 6.6 million family records with more than 8.8 million publications (08/2020)</li> </ul>   |  |             |                                     |
| <b>Coverage</b>          | Application year 2000 to present   |  |             |                                     |
| <b>Updates</b>           | Weekly   |  |             |                                     |
| <b>Language</b>          | English  |  |             |                                     |
| <b>Database Producer</b> | LexisNexis Univentio BV<br>Galileiweg 8<br>2333 BD Leiden<br>The Netherlands<br>Phone: (+31) 88-6390000<br>Email: <a href="mailto:customersupport@univentio.com">customersupport@univentio.com</a><br>Copyright Holder   |  |             |                                     |

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|--------------------------|--|
| <b>Database Supplier</b> | FIZ Karlsruhe<br>STN Europe<br>P.O. Box 2465<br>76012 Karlsruhe<br>Germany<br>Phone: +49-7247-808-555<br>Fax: +49-7247-808-259<br>Email: <a href="mailto:helpdesk@fiz-karlsruhe.de">helpdesk@fiz-karlsruhe.de</a>  |
| <b>Sources</b>           | Patent applications, granted patents, and utilities models published by the Japan Patent Office  |
| <b>User Aids</b>         | <ul style="list-style-type: none"><li>• Online Helps (HELP DIRECTORY lists all help messages available)</li><li>• STNGUIDE</li></ul>   |
| <b>Cluster</b>           | <ul style="list-style-type: none"><li>• AEROTECH</li><li>• ALLBIB</li><li>• AUTHORS</li><li>• CORPSOURCE</li><li>• ENGINEERING</li><li>• FULLTEXT</li><li>• HPATENTS</li><li>• NPS</li><li>• PATENTS</li><li>• PNTTEXT</li></ul> <p>STN Database Clusters information:<br/><a href="http://www.stn-international.com/en/customersupport/customer-support#cluster+%7C+subjects+%7C+features">http://www.stn-international.com/en/customersupport/customer-support#cluster+%7C+subjects+%7C+features</a></p> |

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## Search and Display Field Codes

If multiple search terms are linked with and AND-operator, all terms are searched in the complete database record, i.e. in all publications referring to one application. For a search in a specific publication of the record, connect the search term and the patent kind code with the (L)-proximity operator, e.g. S BOREHOLE/AB, TI, CLM (L) JPA/PK limits the search to Japanese applications JPA.

Fields that allow left truncation are indicated by an asterisk (\*).

### General Search Fields

| Search Field Name   | Search Code         | Search Examples   | Display Codes                   |
|---|---------------------|---|---------------------------------|
| Basic Index* (contains single words from title (TIEN), abstract (AB), detailed description (DETD), claims (CLM), and main claims (MCLM) fields) | None<br>or<br>/BI   | S TRANSISTOR AND ELECTRODE<br>S ACOUSTIC SENSOR<br>S ?TRANSFER? | TIEN, AB,<br>DETD, CLM,<br>MCLM |
| Abstract*   | /AB                 | S BOREHOLE/AB   | AB                              |
| Accession Number  | /AN                 | S 2011006109/AN   | AN                              |
| Agent   | /AG                 | S OHARA YOSHIKAZU/AG  | AG                              |
| Agent Number  | /AGN                | S 100111442/AGN   | AGN                             |
| Application Country<br>(WIPO code and text)   | /AC                 | S JP/AC   | AI                              |
| Application Date (1)  | /AD                 | S AD=JAN 2011   | AI                              |
| Application Number (2)  | /AP                 | S JP2011-101353/AP  | AI                              |
| Application Year (1)  | (or /APPS)<br>/AY   | S AY>=2000  | AI                              |
| Claims*   | /CLM                | S DERIVATION/CLM  | CLM                             |
| Cooperative Patent Classification (3)   | /CPC                | S C12N0009/CPC  | CPC                             |
| Cooperative Patent Classification, Action Date  | /CPC.ACD            | S 20121113/CPC.ACD  | CPC.TAB                         |
| Cooperative Patent Classification, Keyword  | /CPC.KW             | S C12N0009/CPC (S) I/CPC.KW                                     | CPC.TAB                         |
| Cooperative Patent Classification, Version  | /CPC.VER            | S 20130101/CPC.VER  | CPC.TAB                         |
| Document Type<br>(code and text)  | /DT                 | S P/DT  | DT                              |
| Entry Date (1)  | (or /TC)<br>/ED     | S UTILITY MODEL/DT<br>S ED=SEP 2012                             | ED                              |
| Entry Date of Fulltext (1)  | /EDTX               | S 20120926/EDTX   | EDTX                            |
| European Patent Classification (3)  | /EPC                | S H02K0003-12/EPC   | EPC                             |
| Field Availability  | (or /ECLA)<br>/FA   | S AB/FA   | FA                              |
| International Patent Classification<br>(ICM, ICS, IPCI, IPCR) (3)   | /IPC                | S A01B0001-02/IPC   | ICM, ICS,<br>IPCI, IPCR         |
| International Patent Classification (ICM, ICS)  | /IC                 | S A45D/IC   | IC, ICM, ICS                    |
| ICO (in-computer-only) Classification (3)   | /ICO                | S T04L0025:02C /ICO   | ICO                             |
| Inventor  | /IN                 | S MASAKI NAGAOKA/IN   | IN                              |
| Inventor, Country (WIPO code and text)  | (or /AU)<br>/IN.CNY | S MASAKI?/IN<br>S JP/IN.CNY                                     | IN, IN.CNY                      |
| IPC, Initial  | /IPCI               | S B21B0001/IPCI   | IPCI, IPC                       |
| IPC, Keyword Terms  | /IPC.KW             | S INITIAL/IPC.KW  | IPC.TAB                         |
| IPC, Main   | /ICM                | S A63B017-00/ICM  | ICM, IC                         |
| IPC, Reclassified   | /IPCR               | S B21D0005-02/IPCR  | IPCR, IPC                       |
| IPC, Reform   | /IPC.REF            | S A01B0001-16/IPC.REF   | IPC.TAB                         |
| IPC, Secondary  | /ICS                | S A41C003-12/ICS  | ICS, IC                         |
| IPC, Version  | /IPC.VER            | S 7/IPC.VER   | IPC.TAB                         |
| Key Terms (5)   | /KT                 | S GLUCOSE ABSORPTION/KT   | KT                              |
| Language (code and text)  | /LA                 | S JA/LA or S JAPANESE/LA  | LA                              |
| Language, Filing (code and text)  | /LAF                | S JA/LAF<br>S JAPANESE/LAF                                      | LAF                             |
| Main Claim*   | /MCLM               | S ?FRACTURE?/MCLM   | MCLM                            |
| Number of Claims (1)  | /CLMN               | S 5-7/CLMN  | CLMN                            |
| Number of Paragraphs in DETD<br>(Detailed Description) (1)  | /DETN               | S DETN<10   | DETN                            |

## General Search Fields (cont'd)

| Search Field Name                    | Search Code       | Search Examples  | Display Codes |
|--------------------------------------|-------------------|--|---------------|
| Patent Applicant/Patentee <b>(4)</b> | /PA<br>(or /CS)   | S AISIN SEIKI CO LTD/PA  | PA            |
| Patent Applicant, Country            | /PA.CNY           | S JP/PA.CNY  | PA, PA.CNY    |
| Patent Assignee Number               | /PAN              | S 300004681/PAN  | PAN           |
| Patent Country (WIPO code and text)  | /PC               | S JP/PC  | PI            |
| Patent Information Publication Type  | /PIT              | S JPA DOC. LAID OPEN TO PUBL.<br>INSPEC. (PUBLISHED FROM 1971<br>ONWARDS/PIT | PIT           |
| Patent Kind Code                     | /PK               | S JPA/PK   | PI            |
| Patent Number <b>(2)</b>             | /PN<br>(or /PATS) | S JP 2012070634/PN   | PI            |
| Patent Number, Original              | /PNO              | S JP2011062216/PNO   | PNO           |
| Patent Number/Kind Code              | /PNK              | S JP2011062572A/PNK  | PI            |
| Physical Properties                  | /PHP              | S VOLT/PHP (S) TOUCH SCREEN/BI   | KWIC          |
| Priority Country                     | /PRC              | S JP/PRC   | PRN           |
| Priority Date <b>(1)</b>             | /PRD              | S JAPAN/PRC<br>S PRD=MAY, 20 2003<br>S 20030520/PRD                          | PRN           |
| Priority Date, First <b>(1)</b>      | /PRDF             | S 20010614/PRDF  | PRN           |
| Priority Number <b>(2)</b>           | /PRN              | S DE2004-102004063838/PRN  | PRN           |
| Priority Number, Original            | /PRNO             | S US10054698P/PRNO   | PRNO, PRAO    |
| Priority Year <b>(1)</b>             | /PRY              | S 2003/PRY   | PRN           |
| Priority Year, First <b>(1)</b>      | /PRYF             | S 2003-2004/PRYF   | PRN           |
| Publication Date <b>(1)</b>          | /PD               | S PD=MARCH-APRIL 2011  | PI            |
| Publication Year <b>(1)</b>          | /PY               | S PY>2008 AND L1   | PI            |
| Related Patent Country               | /RLC              | S WO/RLC   | RLI           |
| Related Application Number           | /RLN              | S WO2005-JP19917/RLN   | RLI           |
| Related Application Date <b>(1)</b>  | /RLD              | S 20050329/RLD   | RLI           |
| Related Application Year <b>(1)</b>  | /RLY              | S 2005/RLY   | RLI           |
| Title (English)*                     | /TI, /TIEN        | S FLUID###/TIEN  | TI, TIEN      |
| Update Date <b>(1)</b>               | /UP               | S UP=SEP 2012  | UP            |

(1) Numeric search field that may be searched using numeric operators or ranges.

(2) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.

(3) An online thesaurus is available in this field.

(4) Search with implied (S) proximity is available in this field.

(5) Field available for records since 20180813/UP.

## Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

| Search Field Name        | Search Code | Fields Searched | Search Examples      | Display Codes  |
|--------------------------|-------------|-----------------|----------------------|----------------|
| Application Number Group | /APPS       | AP, PRN         | S JP2011-101353/APPS | AI, PRAI, APPS |

## Property Fields<sup>1)</sup>

In JPFULL a numeric search for a specific set of physical properties (/PHP) is available within the full-text fields (TIEN, AB, DETD, and CLM). The numeric values are not displayed as single fields, but highlighted within the hit displays.

Use EXPAND/PHP to search for all available physical properties. A search with the respective field codes will be carried out in all database fields with English text. The /PHP index contains a complete list of codes and related text for all physical properties available for numeric search.

| Field Code     | Property                         | Unit                 | Symbol            | Search Examples                     |
|----------------|----------------------------------|----------------------|-------------------|-------------------------------------|
| /AOS           | Amount of substance              | Mol                  | mol               | S 10 /AOS                           |
| /BIR           | Bit Rate                         | Bit/Second           | bit/s             | S 330/BIR                           |
| /BIT           | Stored Information               | Bit                  | Bit               | S BIT > 3 MEGABIT                   |
| /CAP           | Capacitance                      | Farad                | F                 | S 1-10 MF/CAP                       |
| /CDN           | Current Density                  | Ampere/Square Meter  | A/m <sup>2</sup>  | S CDN>10 A/M**2                     |
| /CMOL          | Molarity, Molar Concentration    | Mol/Liter            | mol/L             | S UREA/BI (S) 2/CMOL                |
| /CON           | Conductance                      | Siemens              | S                 | S 1S-3/CON                          |
| /DB            | Decibel                          | Decibel              | dB                | S DB>50                             |
| /DEG           | Degree                           | Degree               | °                 | S CYLINDER/BI (S) 45/DEG            |
| /DEN           | Density (Mass Concentration)     | Kilogram/Cubic Meter | kg/m <sup>3</sup> | S ANTIBODY/CLM (S) 5E-3-10E-3/DEN   |
| /DEQ           | Dose Equivalent                  | Sievert              | Sv                | S 2/DEQ                             |
| /DOS           | Dosage                           | Milligram/Kilogram   | mg/kg             | S DOS>0.8                           |
| /DV            | Viscosity, dynamic               | Pascal * Second      | Pa * s            | S DV>5000                           |
| /ECD           | Electric Charge Density          | Coulomb/Square Meter | C/m <sup>2</sup>  | S 1 C/M**2 /ECD                     |
| /ECH           | Electric Charge                  | Coulomb              | C                 | S 2-3/ECH                           |
| /ECO           | Electrical Conductivity          | Siemens/Meter        | S/m               | S ECO>800 S/M (5A) METAL            |
| /ELC           | Electric Current                 | Ampere               | A                 | S 1-10/ELC                          |
| /ELF           | Electric Field                   | Volt/Meter           | V/m               | S 650-700/ELF                       |
| /ENE           | Energy                           | Joule                | J                 | S TORQUE (5A) 20 - 30 /ENE          |
| /ERE           | Electrical Resistivity           | Ohm * Meter          | Ohm * m           | S ERE>2                             |
| /FOR           | Force                            | Newton               | N                 | S 50 N /FOR                         |
| /FRE           | Frequency                        | Hertz                | Hz                | S OSCILLAT?/BI (S) 1- 3/FRE         |
| /IU            | International Unit               | none                 | IU                | S IU>1000 (P) ANTIBIOTIC            |
| /KV            | Viscosity, kinematic             | Square Meter/Second  | m <sup>2</sup> /s | S SILICON?/BI (5A) 10E-5 M**2/S /KV |
| /LEN (or /SIZ) | Length, Size                     | Meter                | m                 | S 1-4/LEN                           |
| /LUME          | Luminous Emittance, Illuminance  | Lux                  | lx                | S 10-50/LUME                        |
| /LUMF          | Luminous Flux                    | Lumen                | Lm                | S LUMF>1000                         |
| /LUMI          | Luminous Intensity               | Candela              | cd                | S LUMI<4                            |
| /M             | Mass                             | Kilogram             | kg                | S ALLOY/BI (30A) 1E-10-1E-5/M       |
| /MCH           | Mass to Charge Ratio             | none                 | m/z               | S MCH=100                           |
| /MFD (or /MFS) | Magnetic Flux Density            | Tesla                | T                 | S MFD>102                           |
| /MFR (or /MFL) | Mass Flow Rate                   | Kilogram/Second      | kg/s              | S MFR<0.1                           |
| /MM            | Molar Mass                       | Gram/Mol             | g/mol             | S 2000-3000 G/MOL/MM                |
| /MOLS          | Molality of Substance            | Mol/Kilogram         | mol/kg            | S 01.-10 MOL/KG/MOLS                |
| /MVR           | Melt Volume Rate, Melt Flow Rate | none                 | g/10 min          | S 3/MVR                             |
| /NUC           | Nutrition Content                | none                 | g/100 kcal        | S NUC<100 (P) NUTRIENT              |
| /PER           | Percent (Proportionality)        | none                 | %                 | S POLYMER?/AB (5A) 4/PER            |
| /PERA          | Permittivity, Absolute           | Farad/Meter          | F/m               | S DIELECTRIC/BI (S) 4- 4.1/PERA     |
| /PHV           | pH Value                         | pH                   | pH                | S 7.4-7.6/PHV                       |

## Property Fields (cont'd)

| Field Code       | Property              | Unit                | Symbol            | Search Examples                                   |
|------------------|-----------------------|---------------------|-------------------|---|
| /POW             | Power                 | Watt                | W                 | S LIGHT/BI (S) ENERGY/BI (S)<br>350 WATT/POW      |
| /PRES<br>(or /P) | Pressure              | Pascal              | Pa                | S (VACUUM (5A) DISTILL?)/BI (S)<br>1000-1100/PRES |
| /RAD             | Radioactivity         | Becquerel           | Bq                | S RAD/PHP   |
| /RES             | Electrical Resistance | Ohm                 | Ohm               | S SENSOR /BI (S) 10- 100/RES                      |
| /RSP             | Rotational Speed      | Revolution/Minute   | rpm               | S 2-100/RSP (S) MACHINE/AB                        |
| /SAR             | Area /Surface Area    | Square Meter        | m <sup>2</sup>    | S (COATING? OR FOIL?)/BI (S)<br>10-100/SAR        |
| /SOL             | Solubility            | Gram/100 gram       | g/100 g           | S SOL>20 (10W) WATER                              |
| /STSC            | Surface Tension       | Joule /Square Meter | J/m <sup>2</sup>  | S 60 J/M**2/STSC                                  |
| /TCO             | Thermal Conductivity  | Watt/Meter * Kelvin | W/m * K           | S 1/TCO (S) HEAT?                                 |
| /TEMP<br>(or /T) | Temperature           | Kelvin              | K                 | S (REACTION? (10A) ENZYM?)<br>(S) 5/TEMP          |
| /TIM             | Time                  | Second              | s                 | S ?INCUB?/BI (10A) 10-50/TIM                      |
| /VEL (or<br>/V)  | Velocity              | Meter per Second    | m/s               | S REDUC?/BI (S) 1E-3-5E-3/VEL                     |
| /VELA            | Velocity, angular     | Radian/Second       | rad/s             | S VELA>10   |
| /VLR             | Volumetric Flow Rate  | Cubic Meter/Second  | m <sup>3</sup> /s | S 1-2/VLR (5A) POWDER                             |
| /VOL             | Volume                | Cubic Meter         | m <sup>3</sup>    | S 1E-8-2E-8/VOL.EX                                |
| /VOLT            | Voltage               | Volt                | V                 | S POTENTIAL/CLM (10A) 5E-3 V<br><VOLT<7E-3 V      |

- 1) Exponential format is recommended for the search of particularly high or low values, e.g. 1.8E+7 or 1.8E7 (for 18000000) or 9.2E-8 (for 0.000000092).

## International Patent Classification (/IPC) Thesaurus

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1–7, use the field code followed by the edition number, e.g., /IPC2, for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

| Code              | Content   | Examples                   |
|-------------------|---|----------------------------|
| ADVANCED<br>(ADV) | Advanced Codes for the Core Level IPC Code                      | E A61K0006-06+ADVANCED/IPC |
| ALL               | All Associated Terms (BT, SELF, NT, RT)                         | E C01C003-00+ALL/IPC       |
| BRO (MAN)         | Complete Class  | E C01C+BRO/IPC             |
| BT                | Broader Term (BT, SELF)   | E C01F001-00+BT/IPC        |
| CORE (COR)        | Core Codes for the Advanced Level IPC Code                      | E G08C0019-22+CORE/IPC     |
| ED                | Complete title of the SELF term and IPC manual edition          | E C01F001-00+ED/IPC        |
| HIE               | Hierarchy Term (Broader and Narrower Term)<br>(BT, SELF, NT)    | E C01B003-00+HIE/IPC       |
| INDEX             | Complete title of the SELF term                                 | E C01F001-00+INDEX/IPC     |
| KT                | Keyword Term (catchwords) (SELF, KT)                            | E CYANOGEN+KT/IPC          |
| NEXT              | Next Classification   | E C01C001-00+NEXT5/IPC     |
| NT                | Narrower Terms (SELF, NT)                                       | E C01C+NT/IPC              |
| PREV              | Previous Classification   | E C01C001-12+PREV10/IPC    |
| RT (SIB)          | Related Terms (SELF, RT)  | E C01C003-20+RT/IPC        |
| TI                | Complete Title of the SELF Term and Broader Terms<br>(BT, SELF) | E C01F001-00+TI/IPC        |

## ECLA (/EPC) and ICO Thesauri

This thesaurus is available in the /EPC search field (for ECLA codes) and /ICO search field (for 'in-computer-only' codes). All relationship codes can be used with both the EXPAND and SEARCH commands.

| Relationship Code | Content  | Search Examples                  |
|-------------------|--|----------------------------------|
| ALL               | All usually required terms (BT, SELF, CODE, DEF)                     | E C12M0001-34H2+ALL/EPC          |
| AUTO (1)          | Automatic relationship (BT, SELF, CODE, DEF)                         | E G01J003-443+AUTO/EPC           |
| BT                | Broader terms (BT, SELF)   | E G01J0003-443+BT/EPC            |
| CODE              | Classification Code (SELF, CODE)                                     | E SCRAPER BIASING MEANS+CODE/EPC |
| DEF               | Definition (SELF, DEF)   | E B65G0045-16+DEF/EPC            |
| HIE               | Hierarchy terms (all broader and narrower terms) (BT, SELF, DEF, NT) | E A01B0001+HIE/EPC               |
| KT                | Keyword terms (SELF, KT)   | E LASER+KT/EPC                   |
| MAX               | All associated terms   | E G01J0003-44B+MAX/EPC           |
| NEXT              | Next classification within the same class (SELF, NEXT)               | E A01B0001-24+NEXT/EPC           |
| NEXT(n)           | Next n classification within the same class                          | E A01B0001-24+NEXT3/EPC          |
| NT                | Narrower terms   | E G05B0001-04+NT/EPC             |
| PREV              | Previous Code within the same class (SELF, PREV)                     | E G05B0019-418N1+PREV/EPC        |
| PREV(n)           | Previous n classifications within the same class                     | E G05B0019-418N1+PREV2/EPC       |
| TI                | Complete Title of the SELF Term and Broader Terms (BT, SELF)         | E G05B0001-03+TI/EPC             |

(1) Automatic Relationship is SET OFF. In case of SET REL ON, the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

## CPC Thesaurus

This thesaurus is available in the /CPC search field. All relationship codes can be used with both the EXPAND and SEARCH commands.

| Relationship Code | Content  | Search Examples         |
|-------------------|--|-------------------------|
| ALL               | All usually required terms (BT, SELF, CODE, DEF)                     | E C12M0001-005+ALL/CPC  |
| AUTO (1)          | Automatic relationship (BT, SELF, CODE, DEF)                         | E G01J003-443+AUTO/CPC  |
| BT                | Broader terms (BT, SELF)   | E G01J0003-443+BT/CPC   |
| CODE              | Classification Code (SELF, CODE)                                     | E CARTRIDGES+CODE/CPC   |
| DEF               | Definition (SELF, DEF)   | E B65G0045-16+DEF/CPC   |
| HIE               | Hierarchy terms (all broader and narrower terms) (BT, SELF, DEF, NT) | E A01B0001+HIE/CPC      |
| KT                | Keyword terms (SELF, KT)   | E LASER+KT/CPC          |
| MAX               | All associated terms   | E G01J0003-44+MAX/CPC   |
| NEXT              | Next classification within the same class (SELF, NEXT)               | E A01B0001-24+NEXT/CPC  |
| NEXT(n)           | Next n classification within the same class                          | E A01B0001-24+NEXT3/CPC |
| NT                | Narrower terms   | E G05B0001-04+NT/CPC    |
| PREV              | Previous Code within the same class (SELF, PREV)                     | E G05B0019-00+PREV/CPC  |
| PREV(n)           | Previous n classifications within the same class                     | E G05B0019-00+PREV2/CPC |
| TI                | Complete Title of SELF Term and Broader Terms (BT, SELF)             | E G05B0001-03+TI/CPC    |

(1) Automatic Relationship is SET OFF. In case of SET REL ON, the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

## DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI PA. The fields are displayed or printed in the order requested.

The information of the latest publication is displayed by default. To display the content for all levels of the record you can combine all display fields and formats with the qualifier .M except FA, FAM, CFAM, LS, LS2, RE, SCAN, and TRIAL.

For displaying a particular publication of a database record, you can simply add for certain display field the kind code to the appropriate display format, e.g. ALL.A. Fields that allow this are indicated by a number (3).

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

The default display format is STD.M, i.e., all publication levels of one family in the STD format.

| Format            | Content   | Examples    |
|-------------------|---|-------------|
| AB (ABS)          | Abstract  | D TI AB 1-5 |
| AG                | Agent   | D AG        |
| AGN               | Agent Number                                    | D AGN       |
| AGJA (2)          | Agent (Japanese characters)                     | D AGJA      |
| AI (AP) (1)       | Application Information                         | D AI        |
| AN                | Accession Number                                | D L3 AN     |
| CLM (3)           | Claims  | D CLM       |
| CLMN (2)          | Number of Claims                                | D CLMN      |
| CPC               | Cooperative Patent Classification               | D CPC       |
| CPC.TAB           | CPC, Tabular                                    | D CPC.TAB   |
| DETD (3)          | Detailed Description                            | D DETD      |
| DETN (2)          | Number of Paragraphs in DETD                    | D DETN      |
| DT (TC)           | Document Type                                   | D DT        |
| ED                | Entry Date                                      | D ED        |
| EDTX              | Entry Date of Fulltext                          | D EDTX      |
| EPC               | European Patent Classification                  | D EPC       |
| FA                | Field Availability (for all publication levels) | D FA        |
| IC                | IPC (format contains ICM, ICS)                  | D IC        |
| ICM               | IPC, Main                                       | D IC        |
| ICO               | ICO (in-computer-only) Classification           | D ICO       |
| ICS               | IPC, Secondary                                  | D ICS       |
| IN (AU)           | Inventor (in English)                           | D IN        |
| IN.CNY            | Inventor, Country                               | D IN.CNY    |
| INJA              | Inventor (in Japanese)                          | D INJA      |
| IPCI              | IPC, Initial                                    | D IPCI      |
| IPCR              | IPC, Reclassified                               | D IPCR      |
| LA                | Language  | D LA        |
| LAF               | Language of Filing                              | D LAF       |
| MCLM              | Main Claim                                      | D MCLM      |
| PA (CS)           | Patent Applicant/Patentee (in English)          | D PA        |
| PA.CNY            | Patent Applicant, Country                       | D PA.CNY    |
| PAJA              | Patent Applicant/Patentee (in Japanese)         | D PAJA      |
| PAN               | Patent Assignee Number                          | D PAN       |
| PI (PN, PATS) (1) | Patent Information                              | D PI        |
| PIT               | Patent Information Publication Type             | D PIT       |
| PNO               | Patent Number, Original Format                  | D PNO       |
| PRN (PRAI) (1,5)  | Priority Information                            | D PRN       |
| PRNO (PRAO) (2)   | Priority Number, Original Format                | D PRNO      |
| RLI (RLN)         | Related Patent Information                      | D RLI       |
| TIEN (TI)         | Title (in English)                              | D TIEN      |
| TIJA              | Title (in Japanese)                             | D TIJA      |
| UP                | Update Date                                     | D UP        |



**DISPLAY and PRINT Formats (cont'd)**

| Format                         | Content   | Examples  |
|--------------------------------|---|-----------|
| ALL (1)                        | AN, ED, EDTX, UP, TIEN, TIJA, IN, IN.CNY, INJA, PA, PA.CNY, PAJA, PAN, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, AB, DETD, CLM, KT                               | D ALL     |
| IALL (1)                       | ALL, indented with text labels  | D IALL    |
| DALL (1)                       | ALL, delimited for post processing  | D DALL    |
| APPS (1)                       | AI, RLN, PRAI   | D APPS    |
| BIB (1)                        | AN, ED, EDTX, UP, TI, IN, IN.CNY, PA, PA.CNY, LAF, LA, DT, PIT, PI, AI, RLI, PRAI   | D BIB     |
| IBIB (1)                       | BIB, indented with text labels  | D IBIB    |
| BRIEF (1)                      | AN, ED, EDTX, UP, TIEN, TIJA, IN, IN.CNY, INJA, PA, PA.CNY, PAJA, PAN, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, AB, MCLM, KT                                    | D BRIEF   |
| IBRIEF (1)                     | BRIEF, indented with text labels  | D IBRIEF  |
| FAM (1)                        | AN, table of patent family information (from INPADOCDB)   | D FAM     |
| CFAM (1)                       | AN, Condensed family format (from INPADOCDB)  | D CFAM    |
| IND                            | ED, IPC (ICM, ICS, IPCI, IPCR), CPC, EPC, ICO   | D IND     |
| IPC                            | International Patent Classification (ICM, ICS, IPCI, IPCR)  | D IPC     |
| IPC.TAB                        | IPC, IPC.KW, IPC.VER, in tabular version  | D IPC.TAB |
| CPC.TAB                        | CPC, in tabular version   | D CPC.TAB |
| LS                             | Legal Status (from INPADOCDB)   | D LS      |
| LS2                            | Legal Status (from NPADOCDB), detailed version with display headers   | D LS2     |
| MAX (ALL.M) (1)                | AN, ED, EDTX, UP, TIEN, TIJA, IN, IN.CNY, INJA, PA, PA.CNY, PAJA, PAN, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO, DETD, CLM, KT, FA for all levels of publication | D MAX     |
| IMAX (IALL.M) (1)              | MAX, indented with text labels  | D IMAX    |
| RE                             | Citations (from INPADOCDB)  | D RE      |
| SCAN (4)                       | TI (random display without answer numbers)  | D SCAN    |
| STD (1)                        | AN, ED, EDTX, UP, TIEN, TIJA, IN, IN.CNY, INJA, PA, PA.CNY, PAJA, PAN, LAF, LA, DT, PIT, PI, AI, RLI, PRAI, IPC, CPC, EPC, ICO (STD.M is default)                               | D STD     |
| ISTD (1)                       | STD, indented with text labels  | D ISTD    |
| TRIAL (TRI, SAM, SAMPLE, FREE) | ED, EDTX, UP, TIEN, FA, DETN, CLMN  | D TRIAL   |
| TX                             | DETD, CLM   | D TX      |
| HIT                            | Hit term(s) and field(s)  | D HIT     |
| KWIC                           | Up to 50 words before and after hit term(s) (KeyWord-In-Context)  | D KWIC    |
| OCC                            | Number of occurrences of hit term(s) and field(s) in which they occur   | D OCC     |

- (1) By default, patent numbers, application and priority numbers are displayed in STN Format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN Format, enter SET PATENT STN.
- (2) Custom display only.
- (3) You can combine this display field with the qualifier .PK (Patent Kind Code) to display the content for a certain publication level of a record, e.g. CLM.B2.
- (4) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.
- (5) If priority information is not available for a certain document, this information is taken from the application information of this document and marked with an asterisk (\*).

**SELECT, ANALYZE, and SORT Fields**

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

You can combine all fields except FA with the qualifier .M to SELECT/ANALYZE the content of all publication levels.

**SELECT, ANALYZE, and SORT Fields (cont'd)**

| Field Name   | Field Code    | ANALYZE/<br>SELECT (1) | SORT |
|--|---------------|------------------------|------|
| Abstract   | AB            | Y                      | Y    |
| Accession Number   | AN            | Y                      | Y    |
| Agent  | AG            | Y                      | Y    |
| Agent Number   | AGN           | Y                      | Y    |
| Application Country  | AC            | Y                      | Y    |
| Application Date   | AD            | Y                      | Y    |
| Application Information  | AI (AP, APPS) | Y (2)                  | Y    |
| Application Year   | AY            | Y                      | Y    |
| Claims   | CLM           | Y                      | N    |
| CPC Classification   | CPC           | Y                      | Y    |
| Detailed Description   | DETD          | Y (3)                  | N    |
| Document Type  | DT            | Y                      | Y    |
| Entry Date   | ED            | Y                      | Y    |
| Entry Date Full-text   | EDTX          | Y                      | Y    |
| European Patent Classification   | EPC           | Y                      | Y    |
| Field Availability   | FA            | Y                      | N    |
| International Patent Classification                                      | IC            | Y                      | N    |
| Inventor   | IN (AU)       | Y                      | Y    |
| Inventor, Country  | IN.CNY        | Y                      |      |
| ICO (in-computer-only) Classification                                    | ICO           | Y                      | Y    |
| IPC (ICM, ICS, IPCI, IPCR)   | IPC           | Y                      | Y    |
| IPC, Advanced Level Symbols  | IPC.A         | Y (4)                  | N    |
| IPC, Advanced Level Symbols for Invention                                | IPC.AI        | Y (4)                  | N    |
| IPC, Initial   | IPCI          | Y                      | Y    |
| IPC, Main  | ICM           | Y                      | Y    |
| IPC, Reclassified  | IPCR          | Y                      | Y    |
| IPC, Reform  | IPC.REF       | Y                      | N    |
| IPC, Secondary   | ICS           | Y                      | Y    |
| Key Terms  | KT            | Y                      | N    |
| Language   | LA            | Y                      | Y    |
| Language of Filing   | LAF           | Y                      | Y    |
| Main Claim   | MCLM          | Y                      | N    |
| Number of Claims   | CLMN          | Y                      | Y    |
| Number of Paragraphs in DETD   | DETN          | Y                      | Y    |
| Occurrence Count of Hit Terms  | OCC           | N                      | Y    |
| Patent Assignee/Patentee   | PA (CS)       | Y                      | Y    |
| Patent Assignee, Country   | PA.CNY        | Y                      | Y    |
| Patent Assignee, Address   | PAA           | Y                      | N    |
| Patent Assignee Number   | PAN           | Y                      | Y    |
| Patent Country   | PC            | Y                      | Y    |
| Patent Information Publication Type                                      | PIT           | Y                      | Y    |
| Patent Kind Code   | PK            | Y                      | Y    |
| Patent Number  | PI (PN, PATS) | Y (default)            | Y    |
| Patent Number, Original  | PNO           | Y                      | Y    |
| Patent Number/Kind Code  | PNK           | Y                      | Y    |
| Pre-IPC8 Symbols from the ICM and first IPC8 values from<br>2006-present | IPC.F         | Y (4)                  | Y    |
| Priority Country   | PRC           | Y                      | Y    |
| Priority Date  | PRD           | Y                      | Y    |
| Priority Date, First   | PRDF          | Y                      | Y    |
| Priority Number  | PRN (PRAI)    | Y                      | Y    |
| Priority Number, Original  | PRNO          | Y                      | Y    |
| Priority Year  | PRY           | Y                      | Y    |
| Priority Year, First   | PRYF          | Y                      | Y    |
| Publication Date   | PD            | Y                      | Y    |
| Publication Year   | PY            | Y                      | Y    |

**SELECT, ANALYZE, and SORT Fields (cont'd)**

| Field Name                 | Field Code | ANALYZE/<br>SELECT (1) | SORT |
|----------------------------|------------|------------------------|------|
| Related Patent Country     | RLC        | Y                      | Y    |
| Related Application Number | RLN        | Y                      | Y    |
| Related Application Date   | RLD        | Y                      | Y    |
| Related Application Year   | RLY        | Y                      | Y    |
| Title                      | TIEN       | Y                      | Y    |
| Update Date                | UP         | Y                      | Y    |

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.  
(2) Selects or analyzes application numbers with /AP appended to the terms created by SELECT.  
(3) Appends /BI to the terms created by SELECT.  
(4) Appends /IPC to the terms created by SELECT.

**Sample Records****DISPLAY ALL (STN format)**

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AN      2011029464  JPFULL  ED 20120926  UP 20120926  EDTX 20120926
TIEN    METHOD FOR IDENTIFYING HOST CLONE, METHOD FOR PRODUCING MIXTURE OF
        ANTIBODIES, METHOD FOR CREATING RECOMBINANT HOST CELL, TRANSGENIC
        NON-HUMAN ANIMAL OR PLANT, MIXTURE OF ANTIBODIES, PHARMACEUTICAL
        COMPOSITION, AND USE OF MIXTURE OF ANTIBODIES
TIJA    宿主クロンの識別
        方法、抗体混合物の
        生産方法、組換え宿
        主細胞の作出方法、
        トランスジェニック
        非ヒト動物またはト
        ランスジェニック植
        物、抗体の混合物、
        薬学的組成物、およ
        び抗体の混合物の使
        用
IN      VAN BERKEL PATRICK HENDRIKUS CORNELIS; BRUS RONALD HENDRIK PETER; BOUT
        ABRAHAM; LOGTENBERG TON
INJA    パトリック
        ヘンドリクス
        コルネリス ファン
        ベルケル
        ロナルド ヘンドリッ
        ク ペーター ブルス
        アブラハム ボウト
        トン ログテンベルグ
PA      MERUS BV;
PAJA    メルス ベー ヴェー;
        オランダ国 3 5 8 4
        セーテー ユトレヒト
        ウップサララーン 8
PAN     510098102
LAF     Japanese
LA      Japanese
DT      Patent; (Fulltext)
PIT     JPA DOC. LAID OPEN TO PUBL. INSPEC. [PUBLISHED FROM 1971 ONWARDS]
PI      JP 2011177193      A      20110915
AI      JP 2011-121054      20110530

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**JPFULL**

RLN WO 2003-EP50201 20030527  
 PRAI EP 2002-77953 20020718  
 US 2002-397066P 20020718  
 WO 2003-EP50201 20030527  
 IPCI C12N0015-09 [I,A]; A01H0005-00 [I,A]; A01K0067-27 [I,A]  
 IPCR A61K0039-00 [I,A]; A61K0039-395 [I,A]; A61P0031-04 [I,A]; A61P0031-12  
 [I,A]; A61P0035-00 [I,A]; A61P0035-02 [I,A]; A61P0035-04 [I,A];  
 A61P0037-06 [I,A]; C07K0014-00 [I,A]; C07K0016-00 [I,A]; C07K0016-10  
 [I,A]; C07K0016-28 [I,A]; C07K0016-30 [I,A]; C07K0016-32 [I,A];  
 C12N0015-00 [I,A]; C12P0021-02 [I,A]; C12P0021-08 [I,A]  
 EPC C07K0016-00; C07K0016-10; C07K0016-28A; C07K0016-28A28; C07K0016-28C;  
 C07K0016-28Z; C07K0016-30; C07K0016-32  
 ICO M07K0317:120; M07K0317:210; M07K0317:310; M07K0317:500;  
 M07K0317:510; M07K0317:622; M07K0317:626; M07K0317:730; M07K0319:30

AB

Original

PROBLEM TO BE SOLVED: To provide a method for producing a mixture of antibodies from a single host cell clone.

SOLUTION: The invention provides the methods for producing mixtures of antibodies from a single host cell clone. Additionally, a nucleic acid sequence encoding a light chain, and nucleic acid sequences encoding different heavy chains are expressed in a recombinant host cell. The antibodies in the mixtures suitably comprise identical light chains paired to different heavy chains pairing to the light chain, thereby forming functional antigen binding domains. The mixtures of antibodies are also provided. Such mixtures can be used in a variety of fields.

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DETD

TECHNICAL FIELD. [0001] (Field of invention) as for this invention, field of medicine, furthermore as for details, field of production of antibody, from as for details, it regards the production of the blend of the antibody more.

BACKGROUND ART. [0002] (The background of invention) essential function of immunity type is the defense for infection. Body fluids characteristic immunity system seems like the pathogenic agent, opposes to the molecule which is recognized fault - as oneself, making use of the immunoglobulin. ...

CLM

1. It rearranges the blend of the antibody and in the landlord, it produces being the method where, this method the following: In the rearrangement host cell, at least it is light the chain and ...
2. As the aforementioned rearrangement host cell, the antibody which is produced commonness lightly included the chain, heavily the chain and involution possible commonness where the description above at least 3 kinds differ lightly the nuclear acid arrangement which encodes the chain is included, method of claim 1 statement.
3. Furthermore, the following: The antibody from the host cell, or the process which is collected from the host cell culture It includes, claim method of 1 or 2 statements.

**DISPLAY IBIB**

ACCESSION NUMBER: 2011040790 JPFULL  
 ENTRY DATE: 20120926  
 UPDATE DATE: 20120926  
 ENTRY DATE (FULLTEXT): 20120926  
 TITLE (ENGLISH): USE OF GLASS FOR APPLICATION TO PHOTOVOLTAIC POWER GENERATION  
 INVENTOR(S): FAFNER JORG OTTO FRANZ SPAIGHT BURCKHARD  
 PATENT APPLICANT(S): SCHOTT AG;  
 PATENT APPLICANT NUMBER: 504299782  
 LANGUAGE OF FILING: Japanese

LANGUAGE OF PUBL.: Japanese  
DOCUMENT TYPE: Patent; (Fulltext)  
PATENT INFORMATION TYPE: JPA DOC. LAID OPEN TO PUBL. INSPEC. [PUBLISHED FROM 1971  
ONWARDS]  
PATENT INFORMATION: JP 2011258954 A 20111222  
APPLICATION INFO.: JP 2011-128030 20110608  
PRIORITY INFO.: DE 2010-102010023366 20100610

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